

Grazing Incidence X-Ray Diffraction of Longitudinal and Perpendicular Magnetic Recording Media for HDD

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Longitudinal magnetic recording media for HDD increased the recording density to 60Gbits/in² (80GB/disk), and perpendicular magnetic recording media achieved the recording density of 150Gbits/in². For further increase of the recording density of longitudinal magnetic media, antiferromagnetic coupling (AFC) with a thin Ru layer between top and bottom ferromagnetic thin films was proposed. The optimum thickness of the Ru layer is about 0.8nm. We measured grazing incidence X-ray diffraction (GIXD) profiles in circumferential and radial directions for each layer of AFC media. The X-ray energy was 10keV, and the grazing incidence angle was 0.2 degree. Figure 1 shows in-plane diffraction profiles in the circumferential direction for each layer of AFC media. As shown in the diffraction profile of the Ru layer 0.8nm thick, hcp-Ru(002), (100) and (102) diffraction peaks are observed for the first time from such a thin Ru film of AFC media with hcp-Co peaks from bottom magnetic layer.

For perpendicular magnetic media, we observed for the first time fcc phase with hcp phase in CoCrPt-SiO₂ granular magnetic media, in which 150Gbits/in² recording density was achieved, by using GIXD with ω -axis setting. By reducing fcc phase content in the magnetic layer, the recording density of perpendicular magnetic media would increase up to 400Gbits/in² in near future.

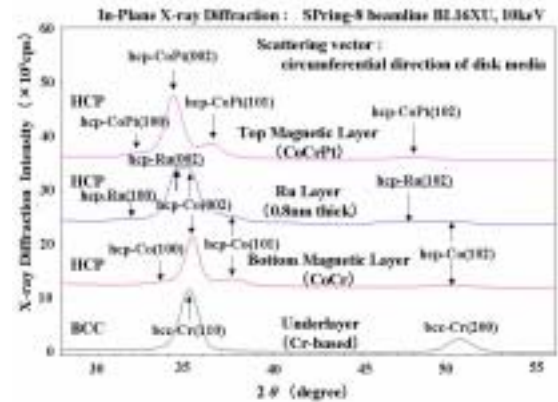


Fig. 1 In-plane diffraction profiles of each layer of longitudinal recording AFC magnetic media.

Grazing Incidence X-Ray Diffraction of Longitudinal and Perpendicular Magnetic Recording Media for HDD

Michio OHSAWA
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My Talk is about

(1) in-plane diffraction of a thin Ru layer in antiferromagnetically coupled (AFC) longitudinal recording media

(2) detection of FCC phase in perpendicular magnetic recording media

by grazing incidence X-ray diffraction (GIXD).

Recent Trend in Magnetic Recording Media for HDD

Longitudinal Media : 60Gbits/in² 120Gbits/in² (2003)
(80GB/disk) (160GB/disk)

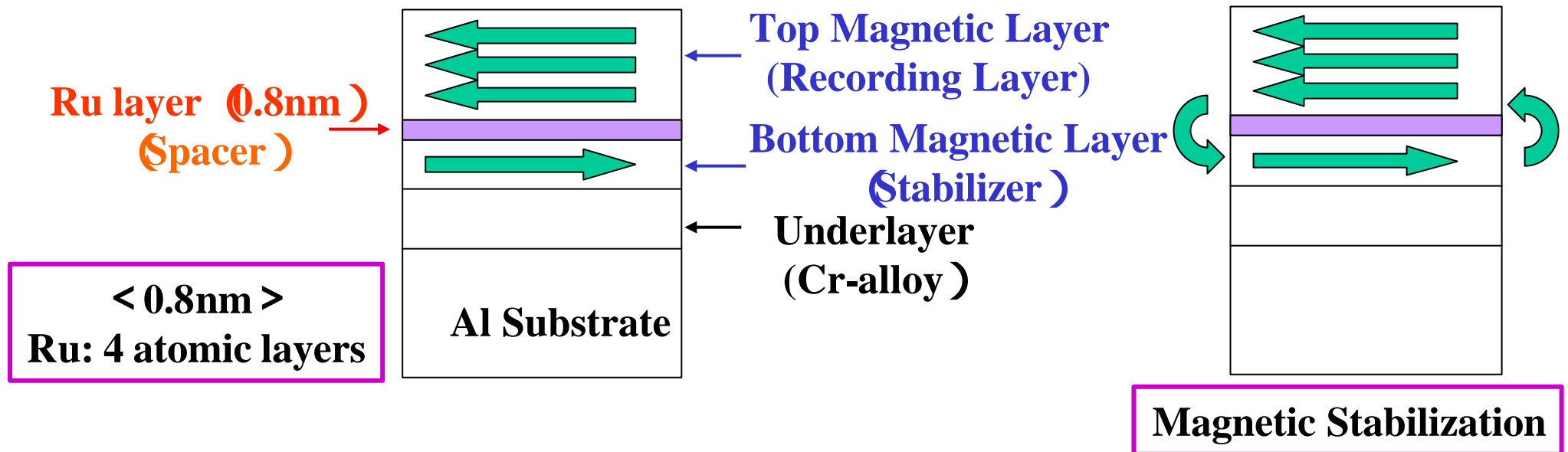
**antiferromagnetic interlayer coupling (AFC) using
a thin Ru layer** has enhanced thermal magnetic stability.

Perpendicular Media : 150Gbits/in² 400Gbits/in² (future)
granular magnetic layer has been developed by Fuji
Electric Co. and is expected to improve recording density.

I will show that GIXD at **undulator beamline** BL16XU in SPring-8 is very powerful for the crystallographic analysis of the polycrystalline thin films in these recently developed media.

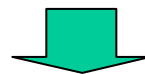
(1) In-Plane X-Ray Diffraction of a thin Ru Layer of AFC Longitudinal Magnetic Recording Media

AFC (antiferromagnetic interlayer exchange coupling) Media



Roles of the Thin (0.8nm) Ru layer

- (1) Spacer for AFC : thin and non-magnetic
- (2) Crystallographic role for the layered structure?



We have tried in-plane diffraction measurements.

X-ray source and Optics

in-vacuum type **undulator** at BL16XU in SPring-8

Si(111) double monochromator

a cylindrical mirror (incident angle: 4.5mrad)

Apparatus for X-ray diffraction

4-circle diffractometer

Measurement conditions for in-plane diffraction

photon energy: 10keV ($\lambda = 1.24 \text{ \AA}$)

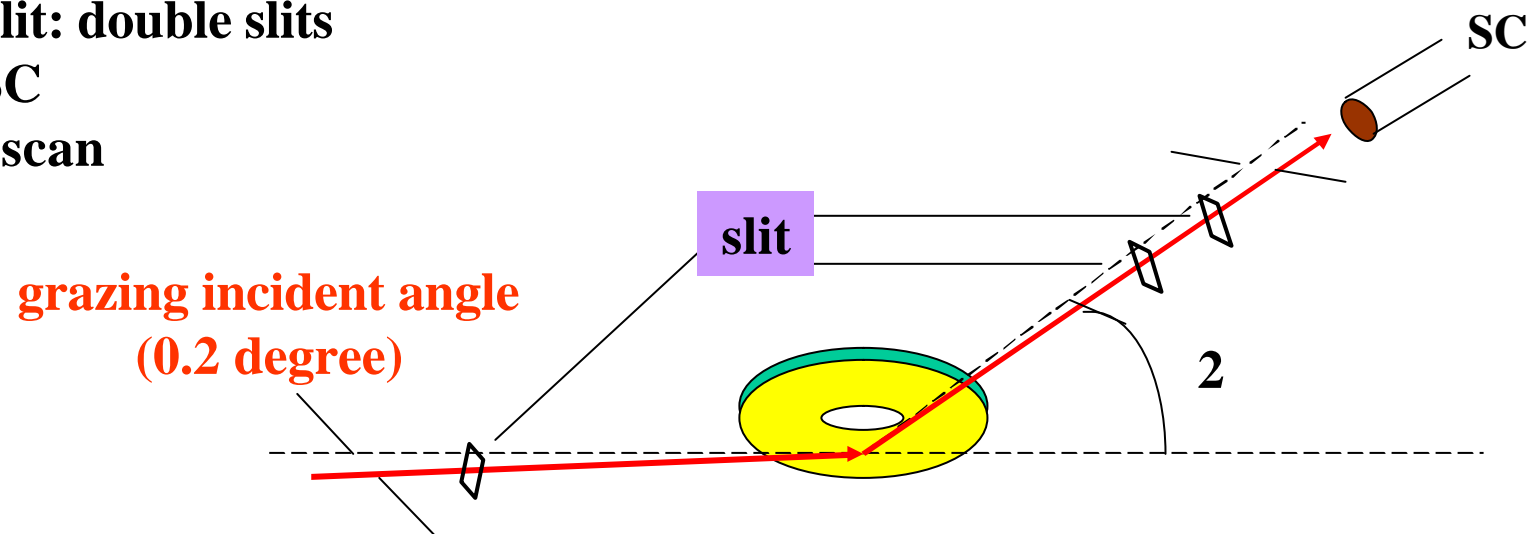
grazing incident angle: 0.2 degree (Total Reflection, Reflectivity > 90%)

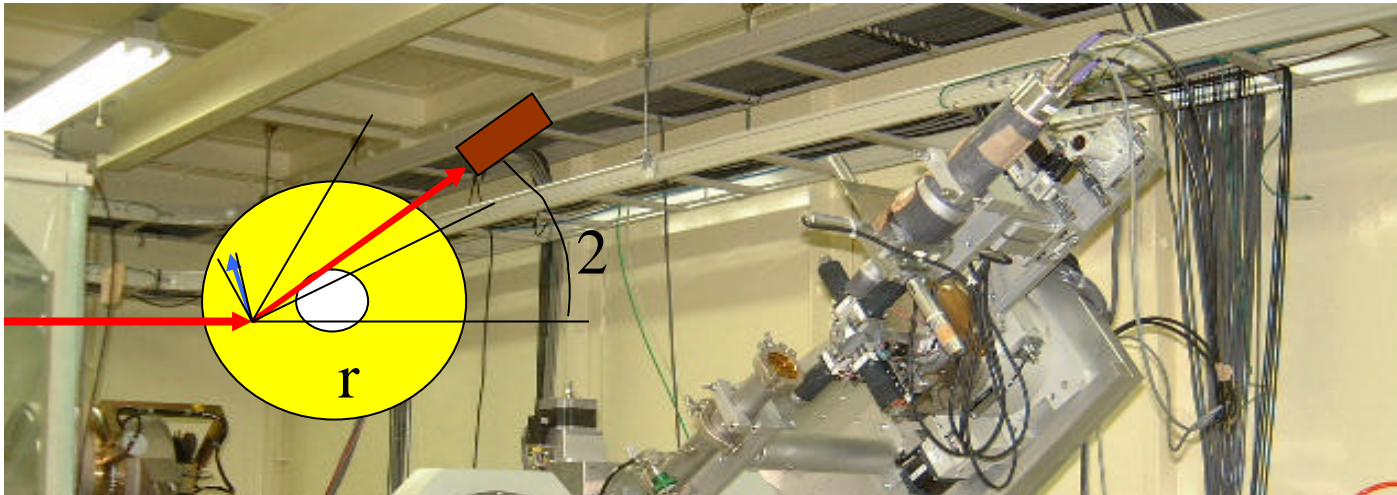
incident slit: 0.1mm (horizontal) \times 1mm (vertical)

receiving slit: double slits

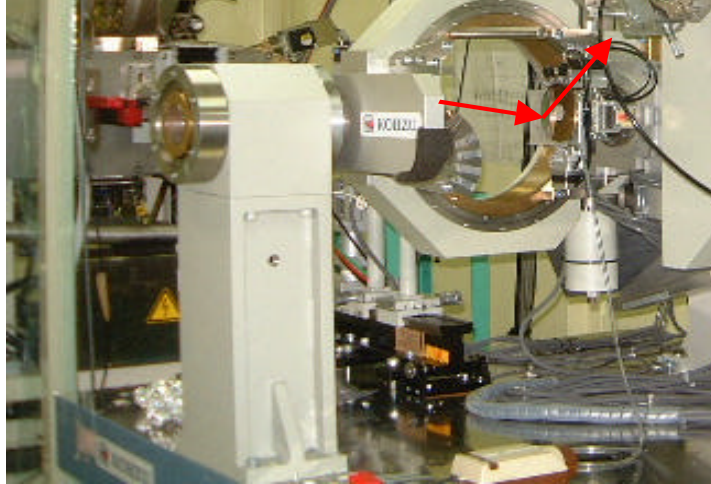
detector: SC

scan: 2 scan

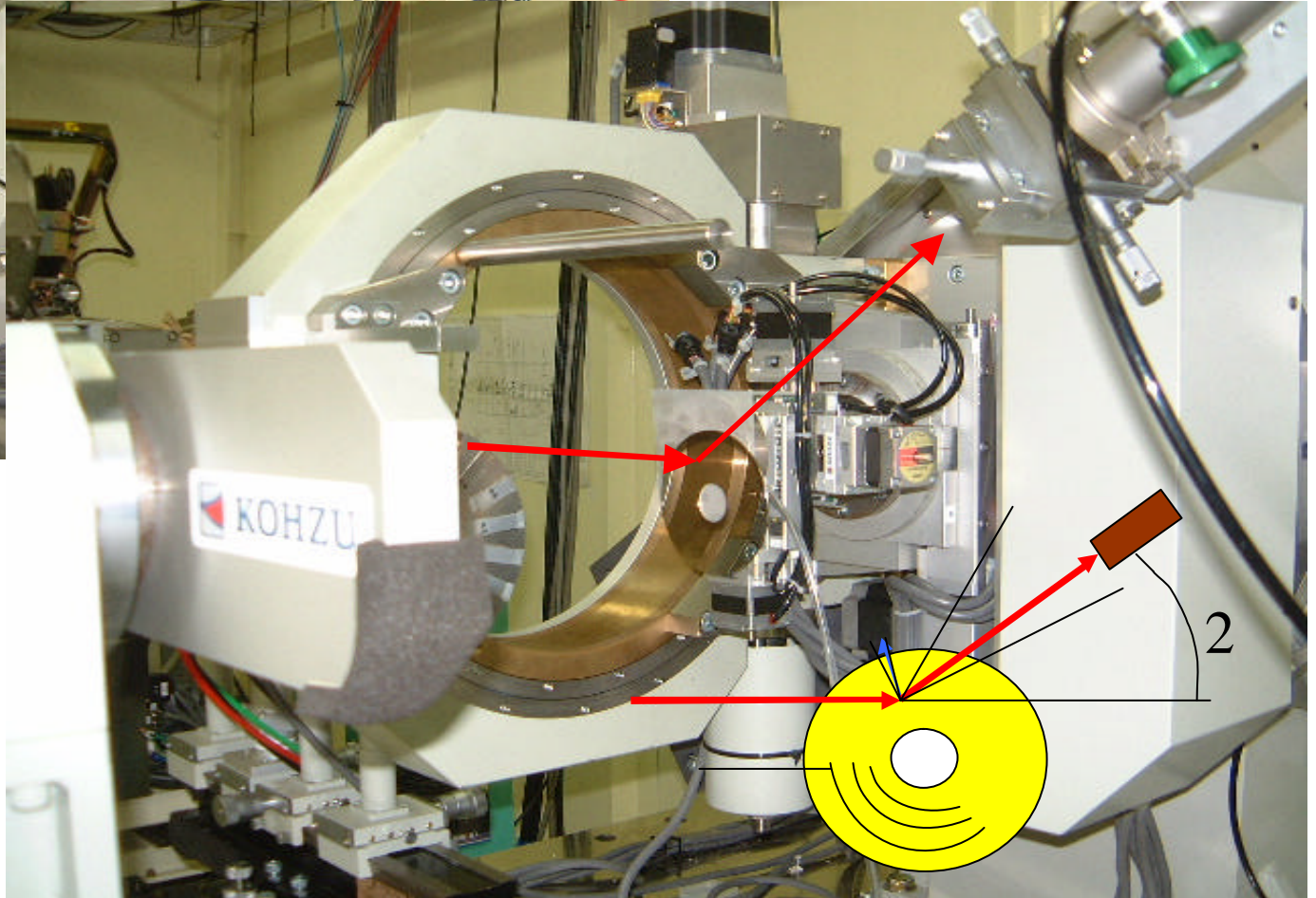




Scattering Vector:
Radial Direction

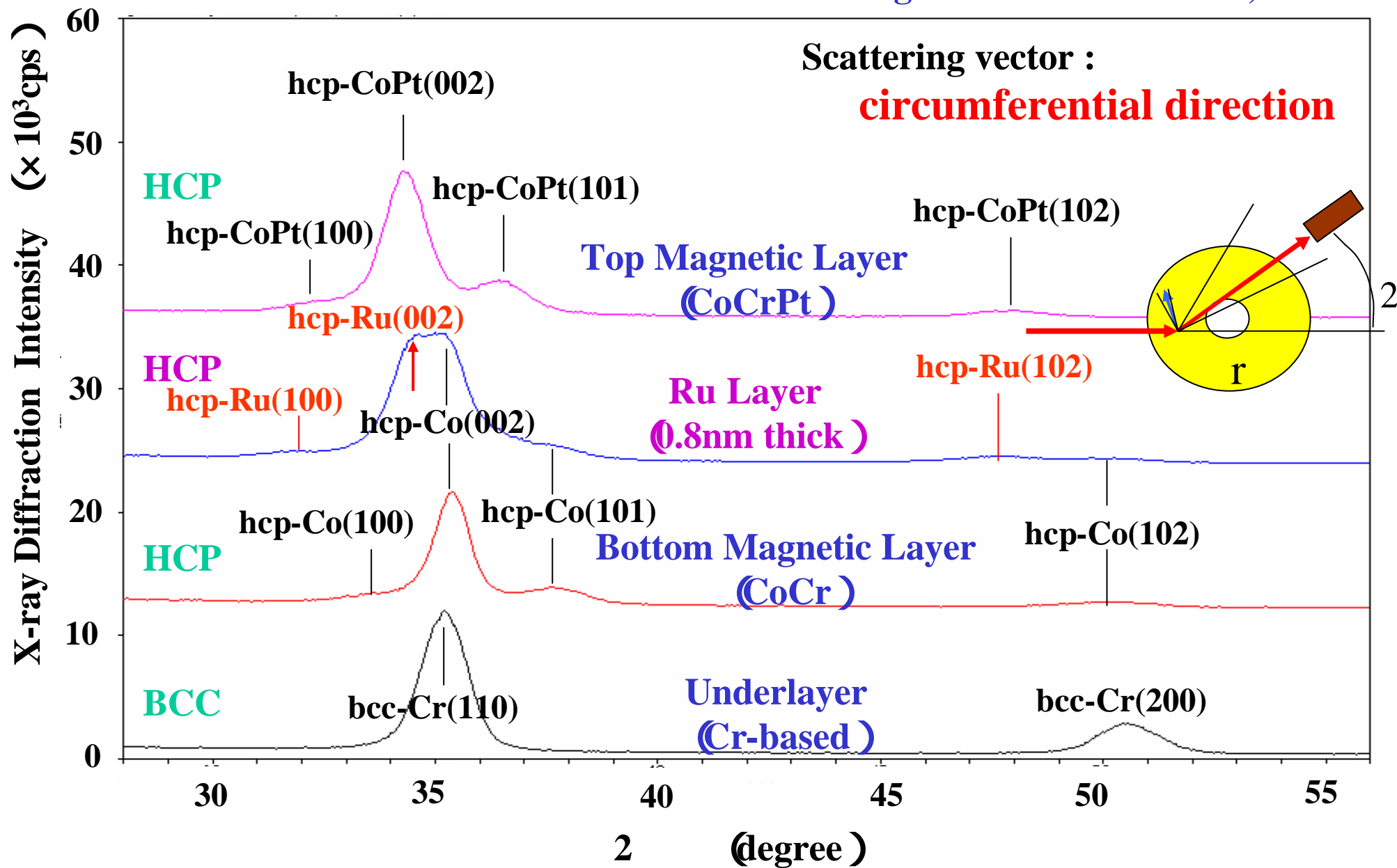


Scattering Vector:
Circumferential
Direction



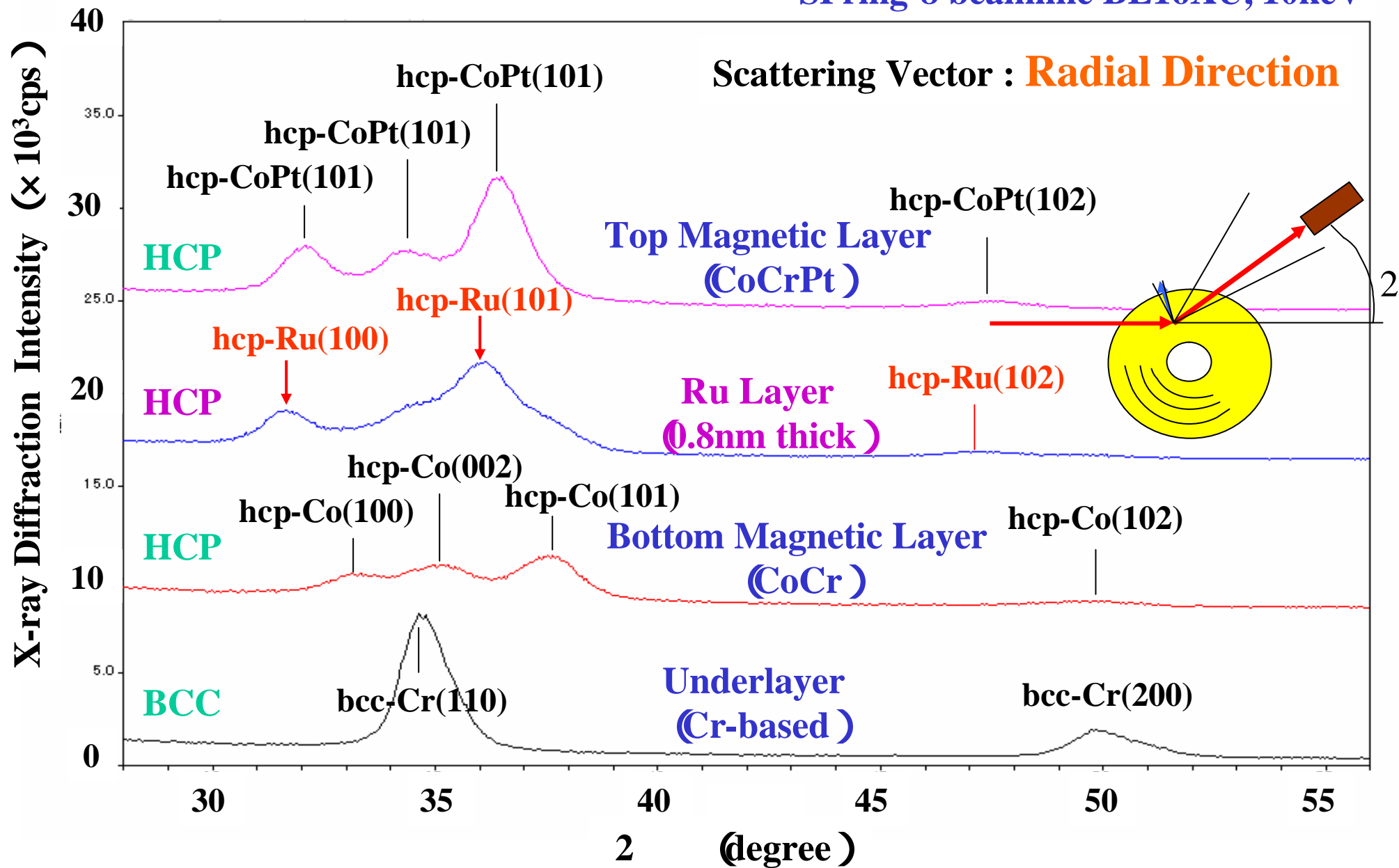
In-Plane X-ray Diffraction of Each Layer of AFC Media:

SPring-8 beamline BL16XU, 10keV

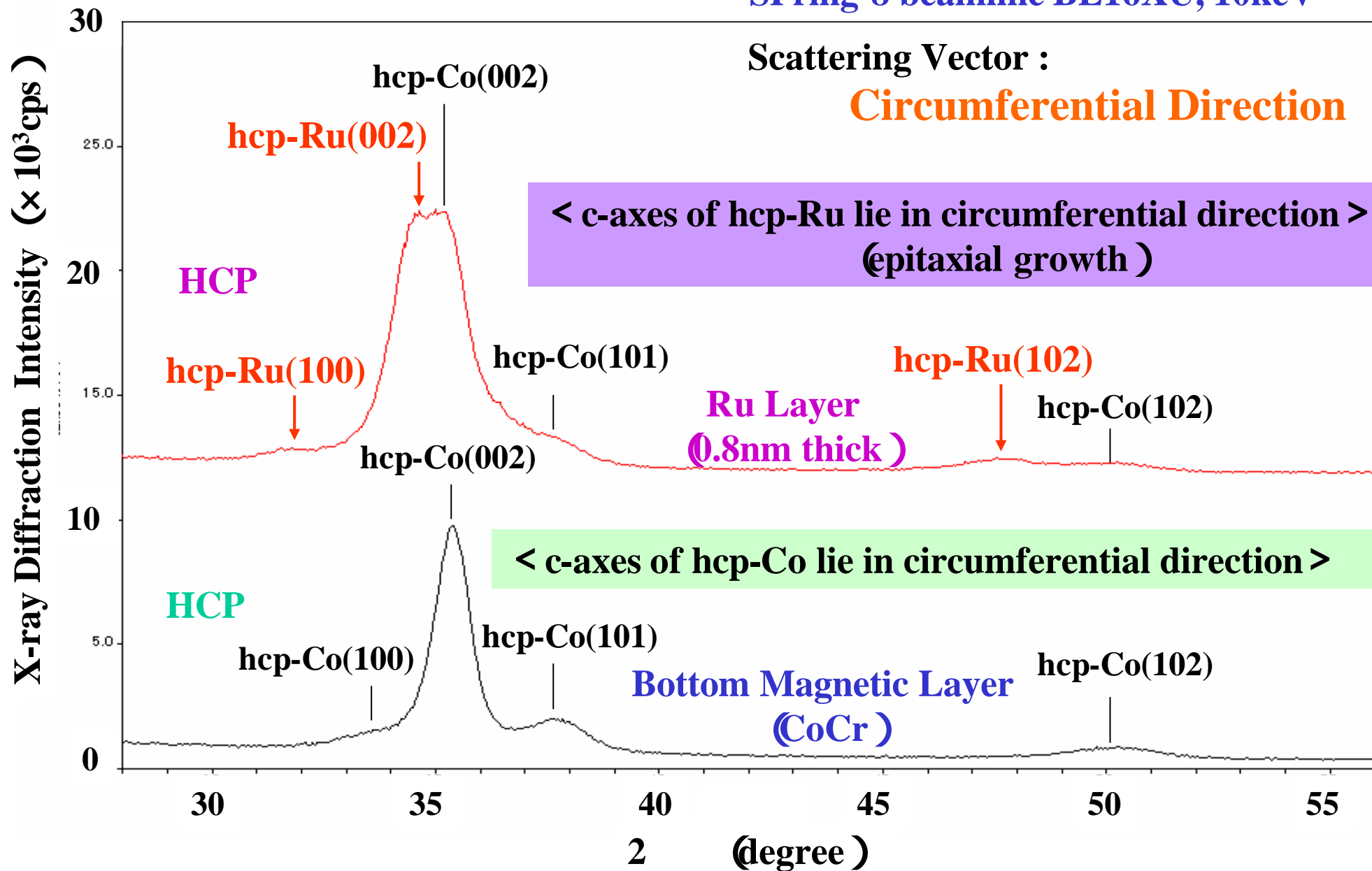


In-Plane X-Ray Diffraction of Each Layer of AFC Media:

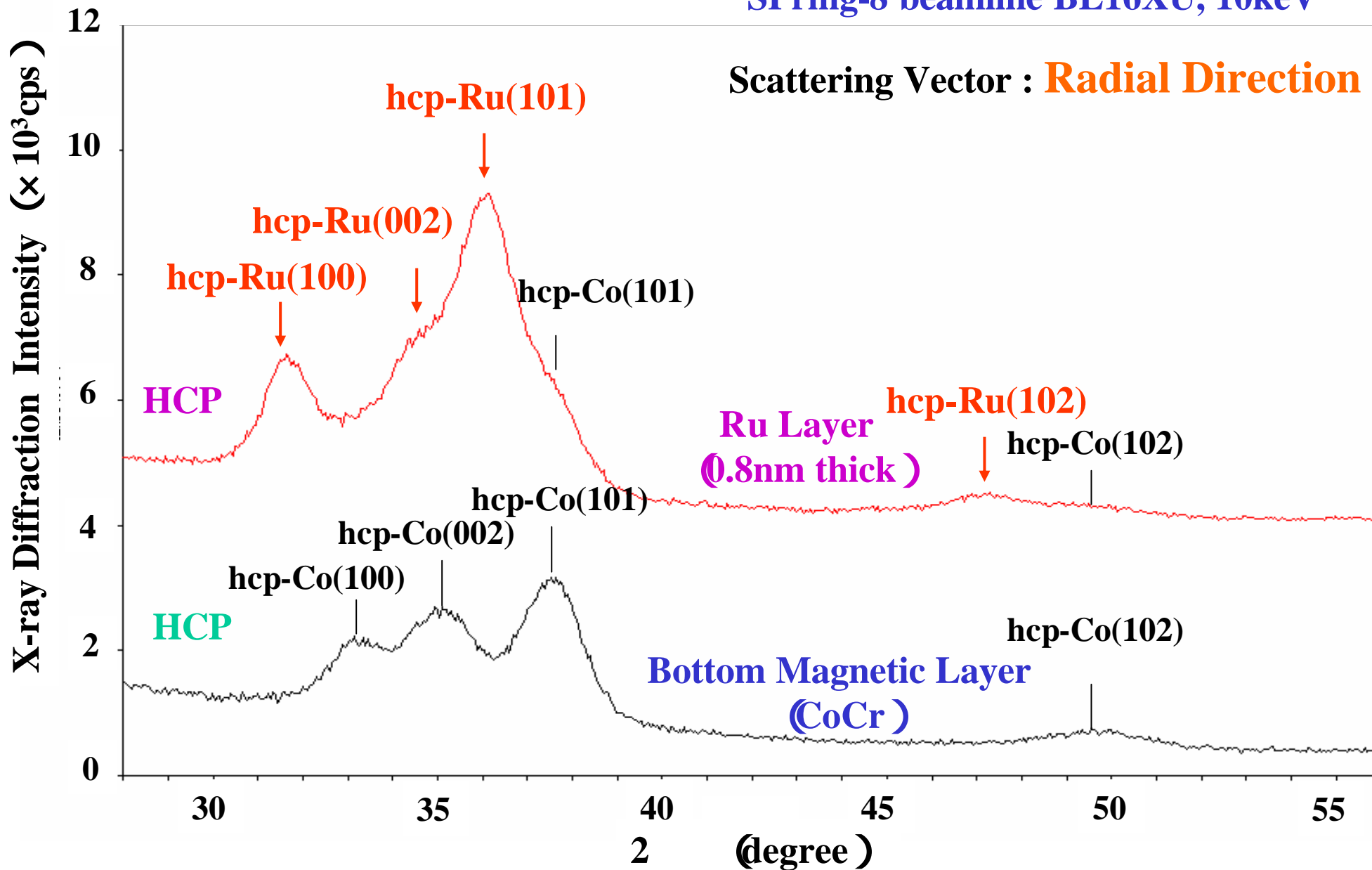
Spring-8 beamline BL16XU, 10keV



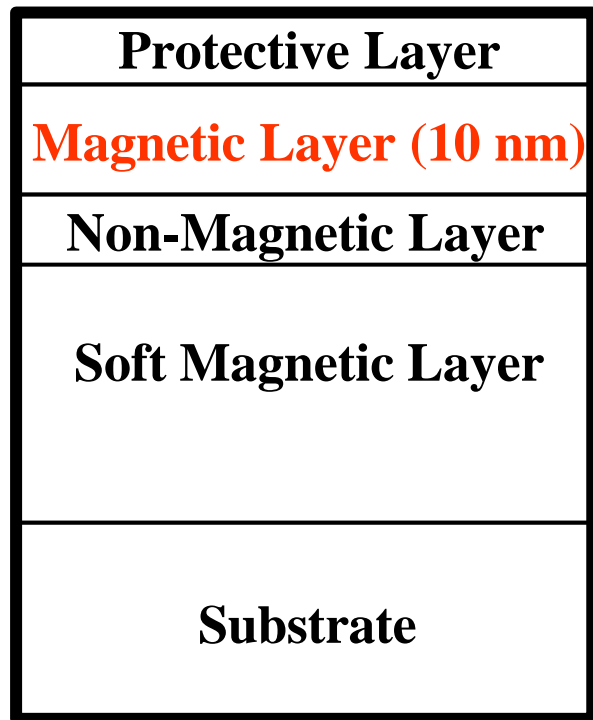
In-Plane X-Ray Diffraction of Ru Layer and Bottom Magnetic Layer: SPring-8 beamline BL16XU, 10keV



In-Plane X-Ray Diffraction of Ru Layer and Bottom Magnetic Layer: SPring-8 beamline BL16XU, 10keV



②) Detection of FCC Phase in Perpendicular Magnetic Recording Media



**FCC Phase in Magnetic Layer
(HCP-Co alloy)**

Low Magnetic Anisotropy
(low thermal stability)

Origin of Noise

Evaluation of FCC phase content in the magnetic layer is important, but difficult for the preferentially oriented HCP-Co alloy thin films.



Layered Structure of
Perpendicular Magnetic Media

We tried GIXD measurements at BL16XU in SPring-8.

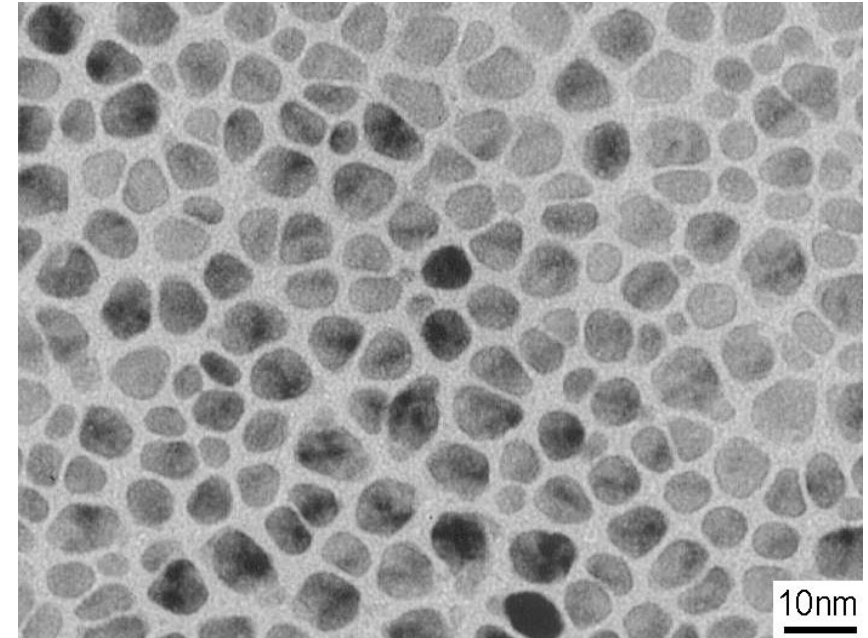
Granular Perpendicular Magnetic Layer

**Perpendicular Magnetic Layer
Developed by Fuji Electric Co.**



**Granular Magnetic Layer
(CoPtCr-SiO₂) Prepared by
Sputtering at RT**

Recording Density: 150Gbits/in²



10nm

Experimental

Samples : CoPtCr-SiO₂ (20nm thick)

Sample A (Pt Content : low)

Sample B (Pt Content : high)

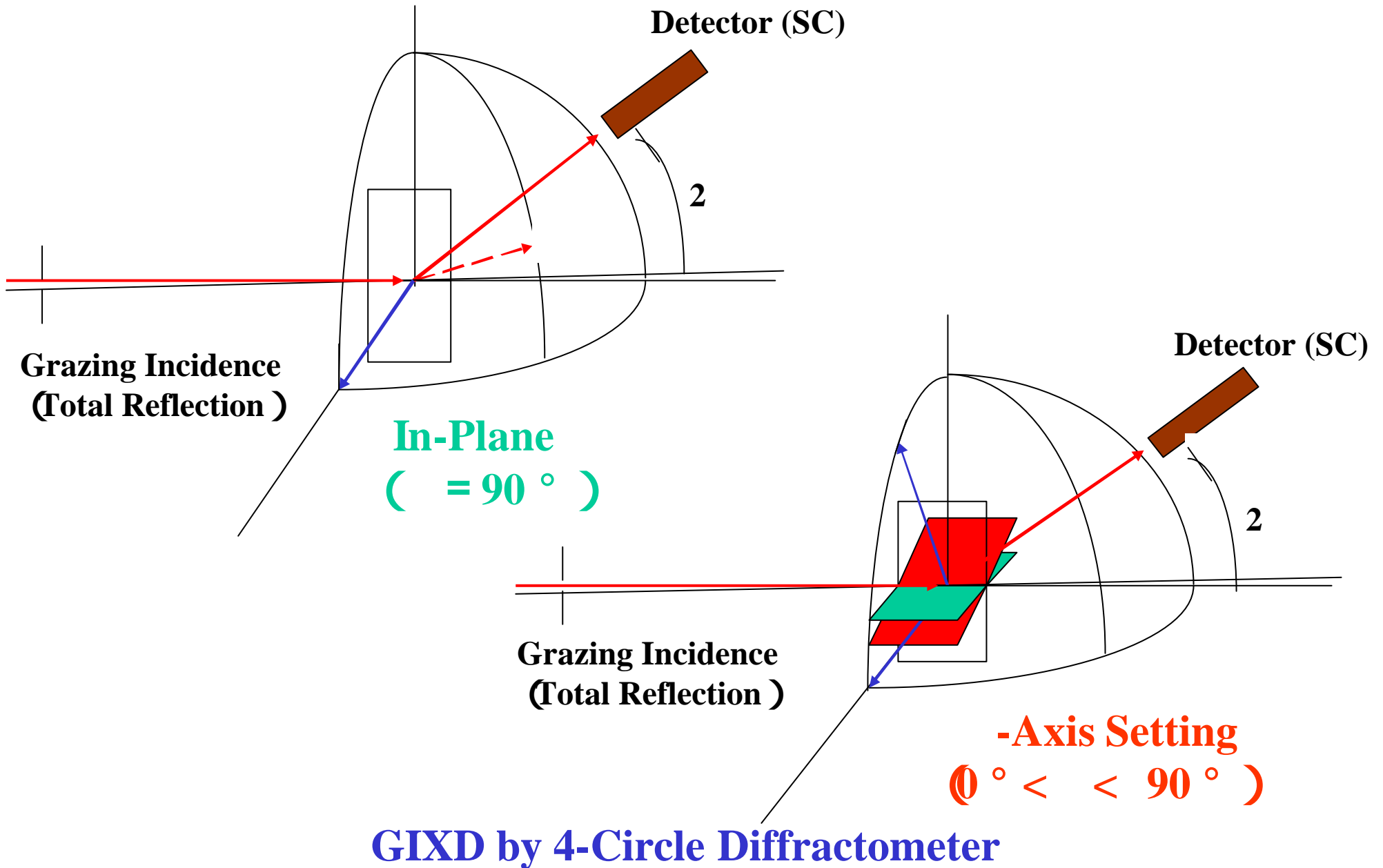
GIXD

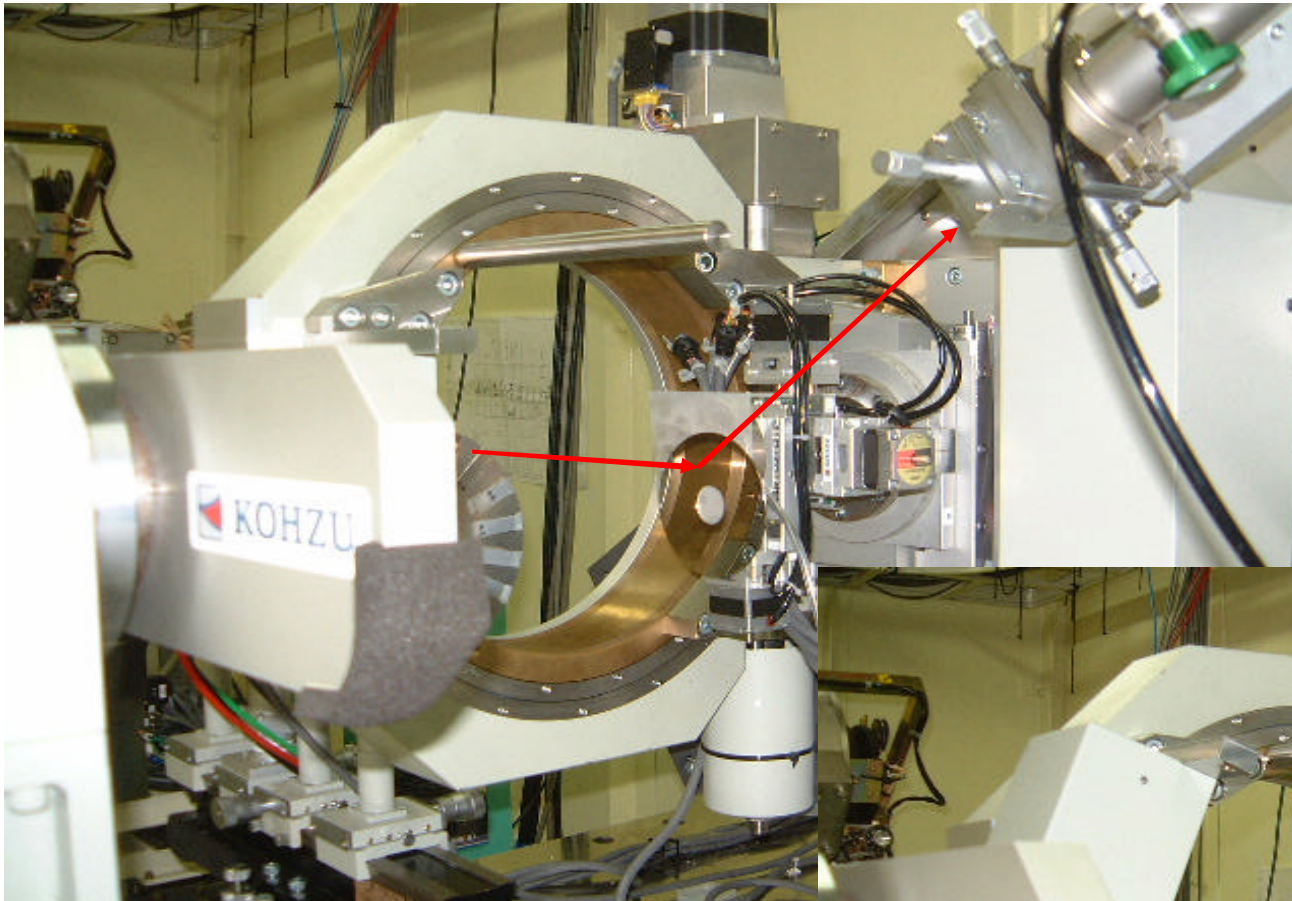
at BL16XU in SPring-8

grazing incident angle: 0.2 degree

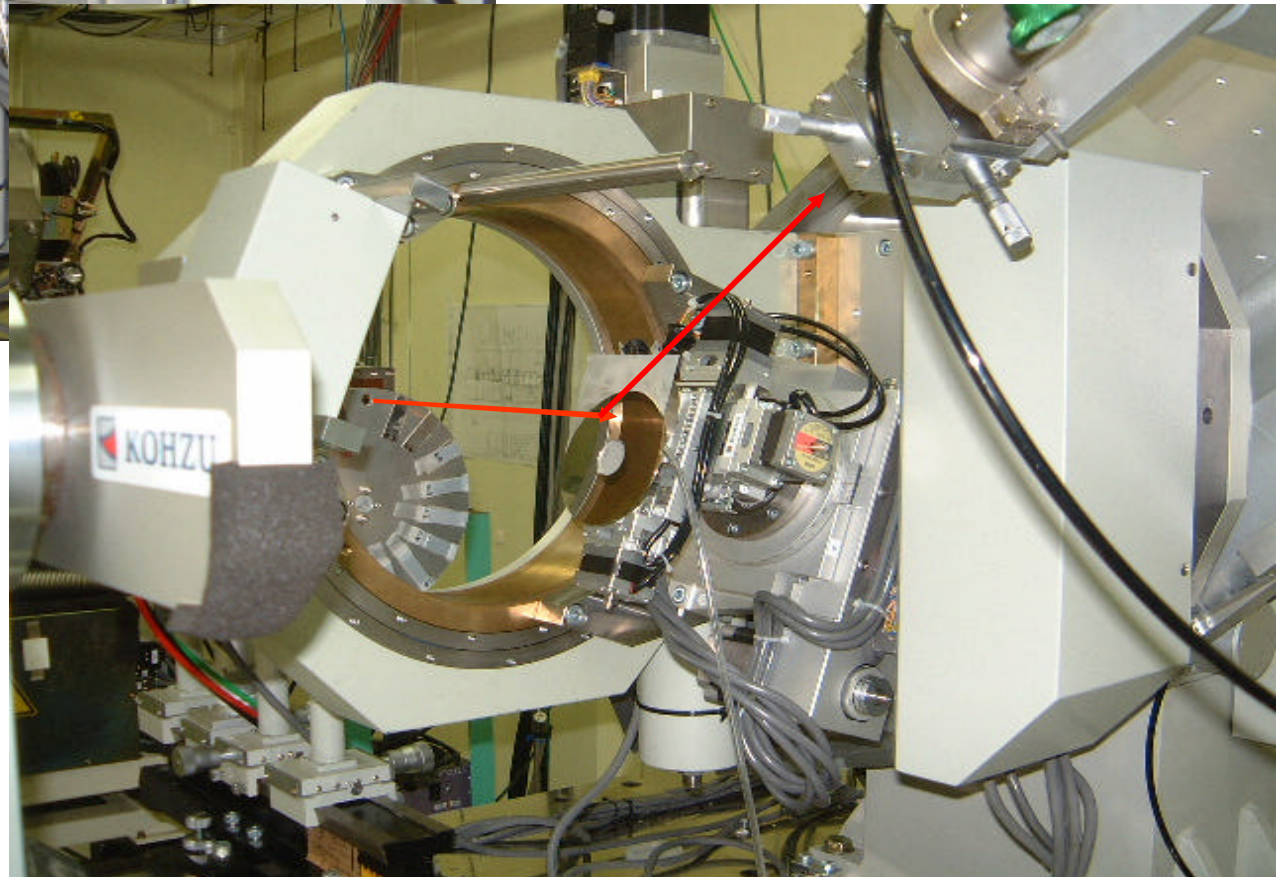
TEM Image (Plane-View)

(average grain size: 6.7nm)





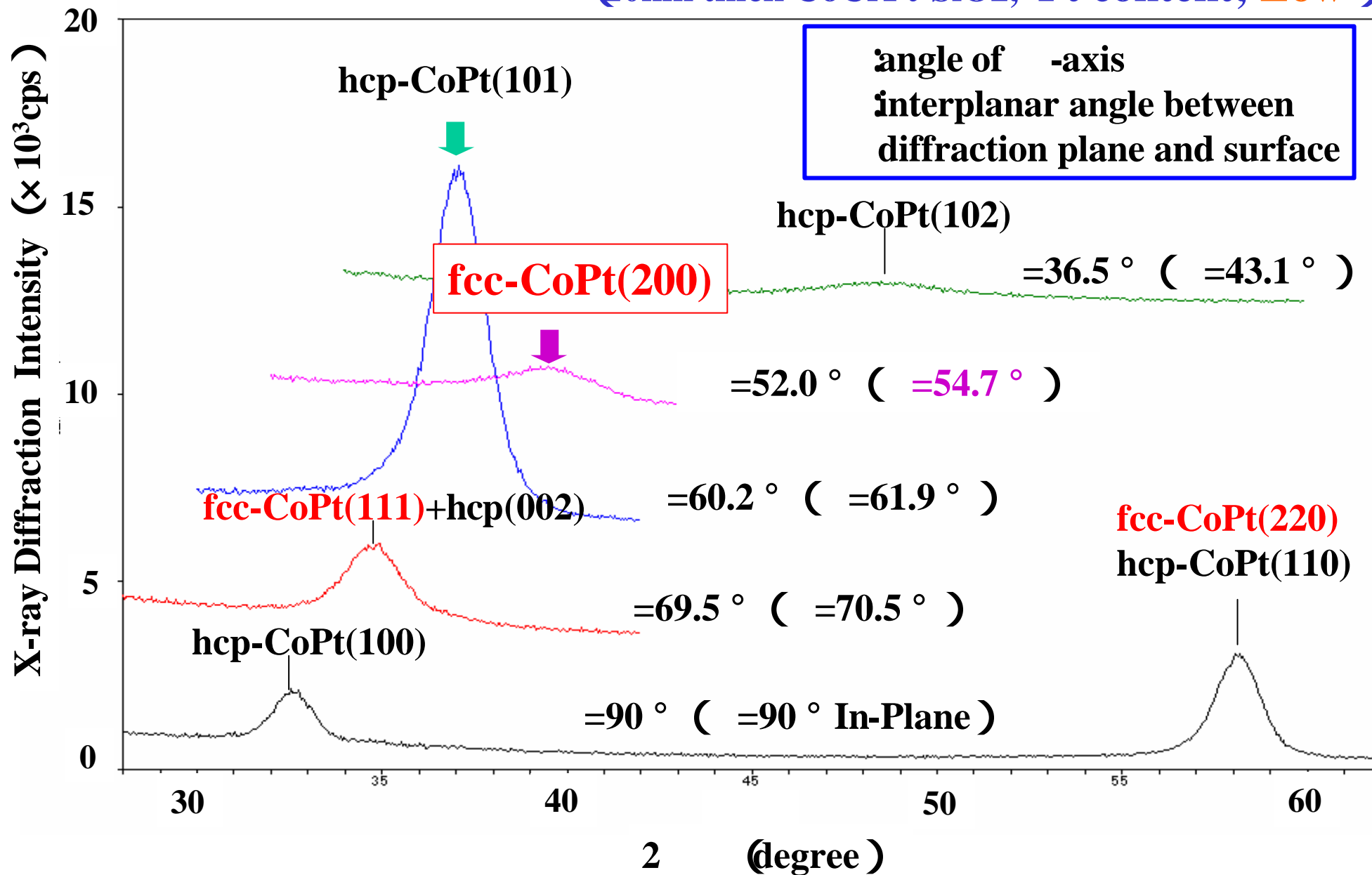
-Axis Setting
($0^\circ < < 90^\circ$)



In-Plane
($= 90^\circ$)

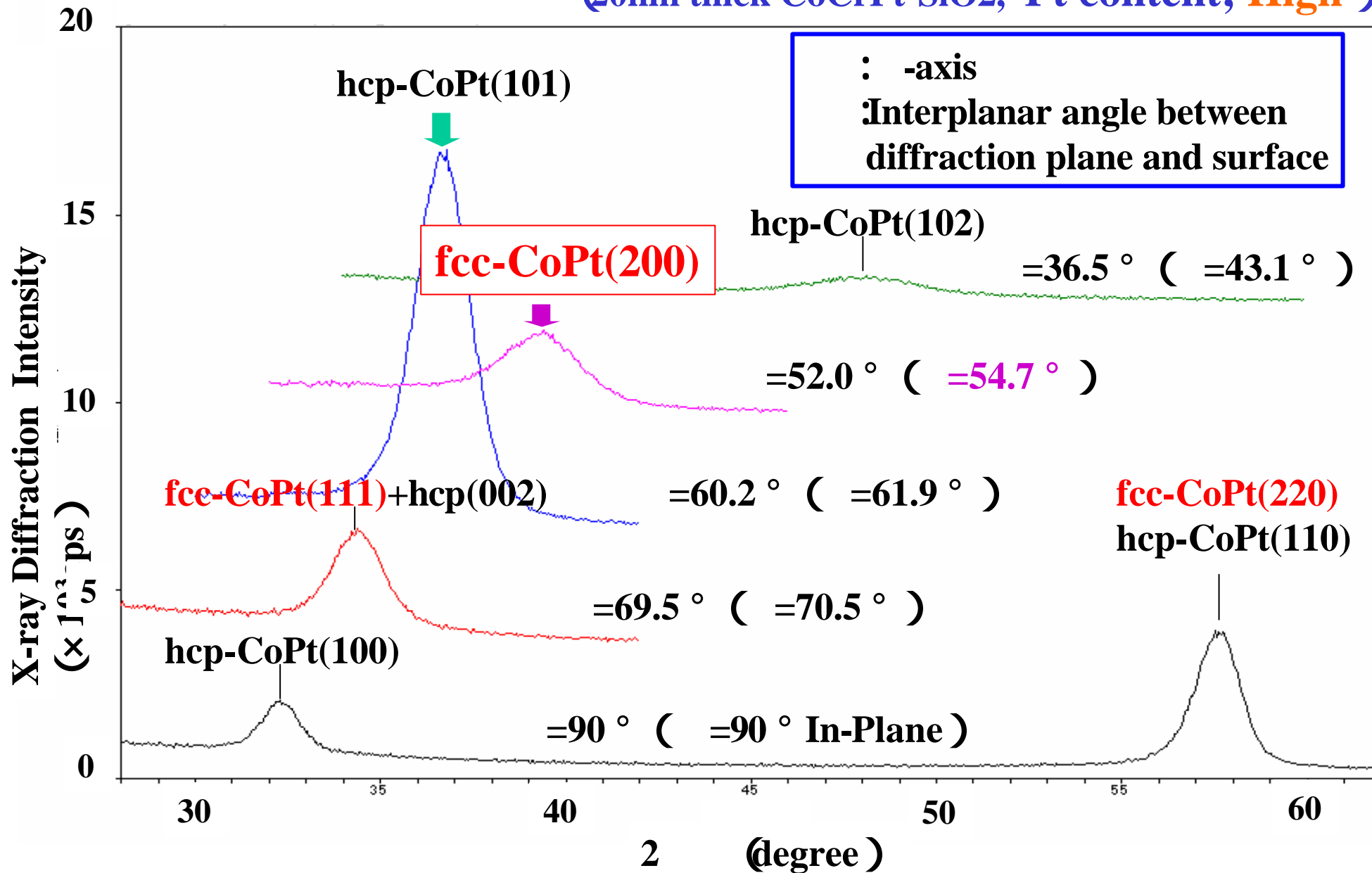
Detection of FCC Phase in **Sample A**

(20nm thick CoCrPt-SiO₂, Pt content; **Low**)

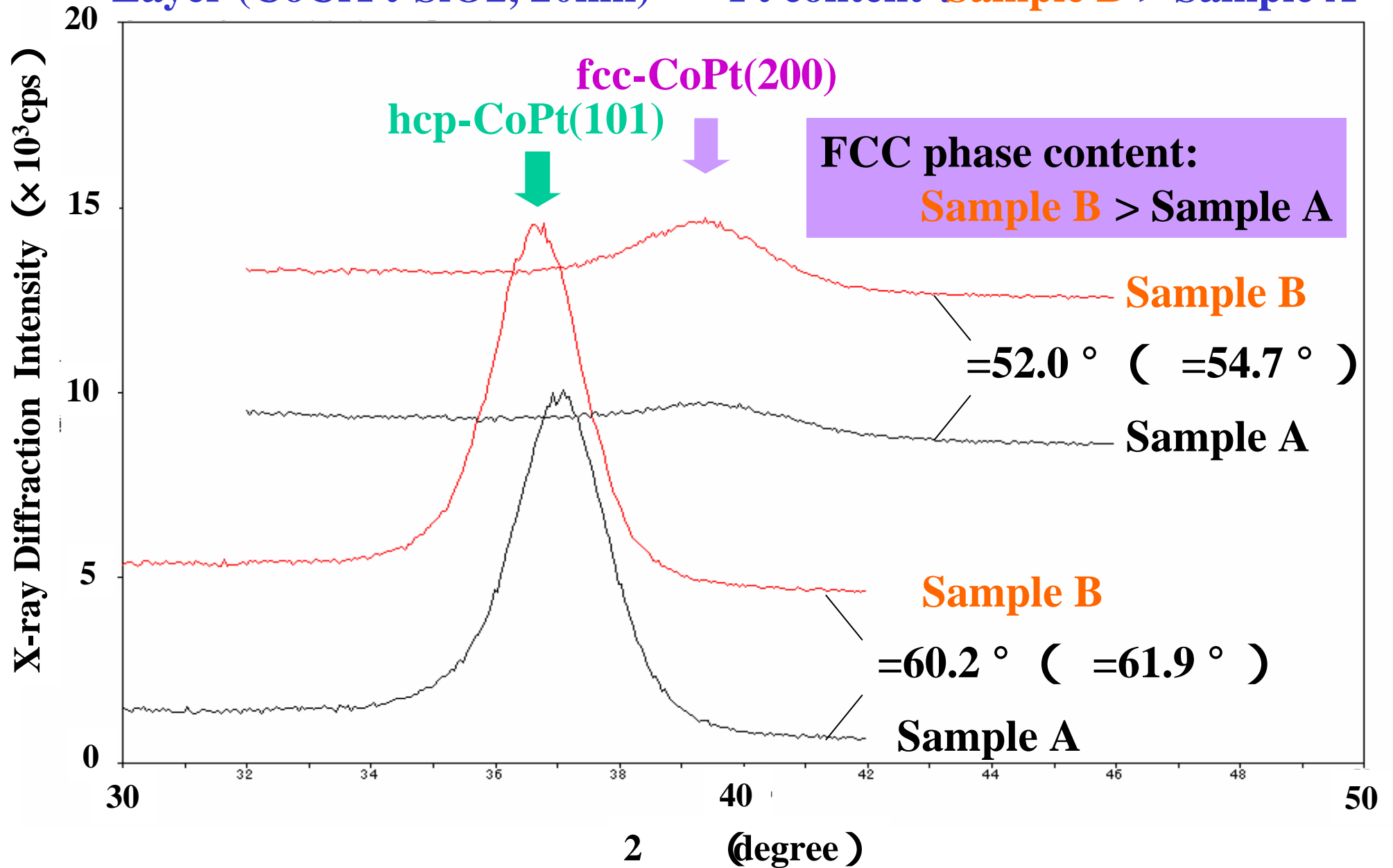


Detection of FCC phase in **Sample B**

(20nm thick CoCrPt-SiO₂, Pt content; **High**)



FCC Phase Dependence on Pt Content in Perpendicular Magnetic Layer (CoCrPt-SiO₂, 20nm) Pt content : **Sample B** > Sample A



About the **longitudinal** magnetic recording media, we estimated for the first time **the crystal structure, preferred orientation and lattice spacing of the 0.8nm thick Ru layer in the AFC media** with the in-plane diffraction at BL16XU in SPring-8. The 0.8nm thick Ru layer grows epitaxially, and have the same crystal orientation as the top and bottom magnetic layers.

About the **perpendicular** magnetic recording media, we detected for the first time **FCC phase in HCP phase granular magnetic layer** with the GIXD ω -axis setting method. The FCC phase content increases with the increasing Pt content in the magnetic layer.

Undulator beamline in SPring-8 is very powerful for the crystallographic analysis of thin films in recently developed magnetic media.